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Morley M. Blouke
Erik Bodegom
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P.O. Box 10, Bellingham, Washington 98227-0010 USA

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7003 Kilworth Lane, Springfield, Virginia, 22151 USA

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Contents

vii *Conference Committee*

SESSION 1 SENSORS I

- 6816 02 **A wide dynamic range CMOS image sensor with an adjustable logarithmic response** [6816-01]
H.-Y. Cheng, B. Choubey, S. Collins, Univ. of Oxford (United Kingdom)
- 6816 03 **Methods to extend the dynamic range of snapshot active pixel sensors** [6816-02]
A. Darmont, Melexis Tessenderlo NV (Belgium)
- 6816 04 **A low-noise wide dynamic range CMOS image sensor with low and high temperatures resistance** [6816-03]
K. Mizobuchi, S. Adachi, J. Tejada, H. Oshikubo, Texas Instruments Japan (Japan);
N. Akahane, S. Sugawa, Tohoku Univ. (Japan)
- 6816 05 **A linear response 200-dB dynamic range CMOS image sensor with multiple voltage and current readout operations** [6816-04]
N. Ide, N. Akahane, S. Sugawa, Tohoku Univ. (Japan)
- 6816 06 **A wide dynamic range CMOS image sensor with dual charge storage in a pixel and a multiple sampling technique** [6816-05]
S. Shafie, S. Kawahito, Shizuoka Univ. (Japan)
- 6816 07 **Ionizing radiation effects on CMOS imagers manufactured in deep submicron process** [6816-06]
V. Goiffon, P. Magnan, Univ. de Toulouse, ISAE (France); F. Bernard, G. Rolland, CNES (France); O. Saint-Pé, EADS Astrium (France); N. Huger, F. Corbière, Univ. de Toulouse, ISAE (France)

SESSION 2 MODELING

- 6816 09 **FDTD-based optical simulations methodology for CMOS image sensor pixels architecture and process optimization** [6816-08]
F. Hirigoyen, STMicroelectronics (France); A. Crocherie, STMicroelectronics (France) and IMEP (France); J. Vaillant, Y. Cazaux, STMicroelectronics (France)
- 6816 0A **Characterization of pixel defect development during digital imager lifetime** [6816-09]
J. Leung, J. Dudas, G. H. Chapman, Simon Fraser Univ. (Canada); Z. Koren, I. Koren, Univ. of Massachusetts, Amherst (USA)

- 6816 0B **Measurements of dark current in a CCD imager during light exposures** [6816-10]
R. Widenhorn, Portland State Univ. (USA) and Digital Clarity Consultants (USA); I. Hartwig,
J. C. Dunlap, Portland State Univ. (USA); E. Bodegom, Portland State Univ. (USA) and Digital
Clarity Consultants (USA)
- 6816 0C **Dark current measurements in a CMOS imager** [6816-11]
W. C. Porter, B. Kopp, J. C. Dunlap, Portland State Univ. (USA); R. Widenhorn, E. Bodegom,
Portland State Univ. (USA) and Digital Clarity Consultants (USA)
- 6816 0D **Noise calculation model and analysis of high-gain readout circuits for CMOS image
sensors** [6816-12]
S. Kawahito, S. Itoh, Shizuoka Univ. (Japan)

SESSION 3 APPLICATIONS I

- 6816 0E **An automated system for performance assessment of airport lighting** [6816-13]
J. Niblock, J.-X. Peng, K. McMenemy, G. Irwin, Queen's Univ. Belfast (United Kingdom)
- 6816 0F **Integrated daylight harvesting and occupancy detection using digital imaging** [6816-14]
A. Sarkar, M. Fairchild, C. Salvaggio, Rochester Institute of Technology (USA)
- 6816 0H **Image formation in metamirror channel structures** [6816-16]
E. Ya. Glushko, Institute of Semiconductor Physics (Ukraine)
- 6816 0I **Diffusion dark current in CCDs and CMOS image sensors** [6816-29]
M. M. Blouke, Ball Aerospace & Technologies Corp. (USA)

SESSION 4 APPLICATIONS II

- 6816 0J **Reference beam method for source modulated Hadamard multiplexing** [6816-17]
L. Streeter, Univ. of Waikato (New Zealand) and AgResearch (New Zealand);
G. R. Burling-Claridge, AgResearch (New Zealand); M. J. Cree, R. Künemeyer, Univ. of
Waikato (New Zealand)
- 6816 0L **Continuously trackable PIV (particle image velocimetry) with correlation image sensor**
[6816-19]
T. Kurihara, S. Ando, The Univ. of Tokyo (Japan)
- 6816 0M **Adaptive optical flow detection using correlation image sensor and frequency-tuned
complex-sinusoidal reference signals** [6816-20]
D. Wei, P. Masurel, T. Kurihara, S. Ando, The Univ. of Tokyo (Japan)
- 6816 0N **A new adaptive image fusion technique for IKONOS satellite imagery** [6816-21]
J. W. Choi, H. J. Kim, K. Y. Ryu, Y. I. Kim, Seoul National Univ. (South Korea)

SESSION 5 SENSORS II

- 6816 0Q **Mitigating polarization effects in on-die diffractive optics for a CMOS image sensor**
[6816-24]
C. Thomas, R. Hornsey, York Univ. (Canada)
- 6816 0R **A 800(H) x 600(V) high sensitivity and high full well capacity CMOS image sensor with active pixel readout feedback operation** [6816-25]
W. Lee, N. Akahane, Tohoku Univ. (Japan); S. Adachi, K. Mizobuchi, Tohoku Univ. (Japan) and Texas Instruments Japan (Japan); S. Sugawa, Tohoku Univ. (Japan)
- 6816 0S **Auto-adaptative LSB technique for in-pixel analog to digital conversion** [6816-28]
A. Peizerat, A. Martin, M. Tchagaspian, V. Nguyen, CEA/LETI, Minatec (France)

INTERACTIVE PAPER AND SYMPOSIUM DEMONSTRATION SESSION

- 6816 0U **In vivo microscopic x-ray imaging in rat and mouse using synchrotron radiation** [6816-27]
K. Umetani, Japan Synchrotron Radiation Research Institute (Japan); T. Sakurai, T. Kondoh, Kobe Univ. (Japan)

Author Index

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- 2 Modeling
Alice L. Reinheimer, e2v (USA)
- 3 Applications I
Morley M. Blouke, Ball Aerospace & Technologies Corporation (USA)
- 4 Applications II
Erik Bodegom, Portland State University (USA) and Digital Clarity
Consultants (USA)
- 5 Sensors II
Valérie Nguyen, CEA/MINATEC-LETI (France)

